

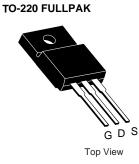
SSS5N80A-VB Datasheet

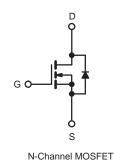
N-Channel 800V (D-S) Super Junction Power MOSFET

PRODUCT SUMMA	RY	
V _{DS} (V)	800)
R _{DS(on)} (Ω)	$V_{GS} = 10 V$	1.2
Q _g (Max.) (nC)	200)
Q _{gs} (nC)	24	
Q _{gd} (nC)	110)
Configuration	Sing	le

FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- · Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC





ABSOLUTE MAXIMUM RATINGS (T C	= 25 °C, unl	ess otherwis	se noted)		
PARAMETER		SYMBOL	LIMIT	UNIT	
Drain-Source Voltage		V _{DS}	800	V	
Gate-Source Voltage		V _{GS}	± 30		
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C		5	
Continuous Drain Current	V _{GS} at 10 V	T _C = 100 °C		3.9	A
Pulsed Drain Current ^a			I _{DM}	21	
Linear Derating Factor				1.5	W/°C
Single Pulse Avalanche Energy ^b			E _{AS}	770	mJ
Repetitive Avalanche Current ^a			I _{AR}	7.8	A
Repetitive Avalanche Energy ^a		E _{AR}	19	mJ	
Maximum Power Dissipation $T_C = 25 \ ^{\circ}C$		PD	190	W	
Peak Diode Recovery dV/dt ^c		dV/dt	2.0	V/ns	
Operating Junction and Storage Temperature Rang	tion and Storage Temperature Range T _J , T _{stg} - 55 to + 150		°C		
Soldering Recommendations (Peak Temperature)	for	10 s		300 ^d	
Mounting Torquo	6-32 or M3 screw 10		lbf ∙ in		
Mounting Torque				1.1	N · m

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. V_{DD} = 50 V, starting T_J = 25 °C, L = 23 mH, R_g = 25 Ω , I_{AS} = 7.8 A (see fig. 12). c. I_{SD} \leq 7.8 A, dl/dt \leq 140 A/µs, V_{DD} \leq 600 V, T_J \leq 150 °C.

d. 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply

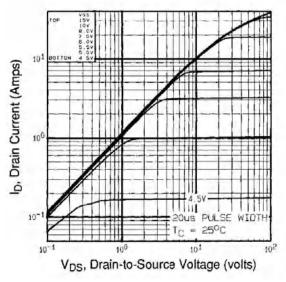


THERMAL RESISTANCE RATI	NGS							
PARAMETER	SYMBOL	TYP.		MAX.			UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-		40				
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.24 - - 0.65				°C/W		
Maximum Junction-to-Case (Drain)	R _{thJC}							
SPECIFICATIONS (T _J = 25 °C, u	nless otherwi	se noted)						
PARAMETER	SYMBOL	TES	T CONDIT	IONS	MIN.	TYP.	MAX.	UNIT
Static								•
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} :	= 0 V, I _D =	250 µA	800	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C,	I _D = 1 mA	-	0.98	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D =	250 µA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}		$V_{GS} = \pm 20$	V	-	-	± 100	nA
		V _{DS} =	= 800 V, V _G	_{as} = 0 V	-	-	100	<u> </u>
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 640 \	/, V _{GS} = 0 V	∕, T _J = 125 °C	-	-	500	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V		₀ = 3.7 A ^b	-	1.2	-	Ω
Forward Transconductance	g fs	V _{DS} =	= 100 V, I _D =	= 3.7 A ^b	5.6	-	-	S
Dynamic		1			<u> </u>	<u></u>	I	1
Input Capacitance	C _{iss}		V _{GS} = 0 V	1	-	3100	-	
Output Capacitance	C _{oss}		$V_{GS} = 0.0$ $V_{DS} = 25.0$		-	800	-	pF
Reverse Transfer Capacitance	C _{rss}	f = 1	.0 MHz, se	e fig. 5	-	490	-	
Total Gate Charge	Qg				-	-	200	
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V		A, $V_{DS} = 400 V$, ig. 6 and 13 ^b	-	-	24	nC
Gate-Drain Charge	Q _{gd}		Seel	ig. 6 and 15-	-	-	110	
Turn-On Delay Time	t _{d(on)}				-	19	-	
Rise Time	t _r	V _{DD} =	= 400 V, I _D	= 3.8 A,	-	38	-	
Turn-Off Delay Time	t _{d(off)}	$R_{g} = 6.2 \Omega, R_{D} = 52 \Omega$ see fig. 10 ^b		-	120	-	ns	
Fall Time	t _f	-	see lig. It)-	-	39	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from		-	5.0	-		
Internal Source Inductance	L _S	package and die contact	center of		-	13	-	nH
Drain-Source Body Diode Characteristic	s					•		•
Continuous Source-Drain Diode Current	I _S	MOSFET sym showing the	bol		-	-	5.0	^
Pulsed Diode Forward Current ^a	I _{SM}	integral revers p - n junction			-	-	21	A
Body Diode Voltage	V _{SD}	T _J = 25 °C	C, I _S = 3.8 A	A, V _{GS} = 0 V ^b	-	-	1.8	V
Body Diode Reverse Recovery Time	t _{rr}	T.=	25 °C, I _F =	: 3.8 A.	-	650	980	ns
Body Diode Reverse Recovery Charge	Q _{rr}	dl,	/dt = 100 A	õs ^b	-	3.8	5.7	μC
Forward Turn-On Time	t _{on}	Intrinsic tu	rn-on time	is negligible (turn	-on is dor			

Notes

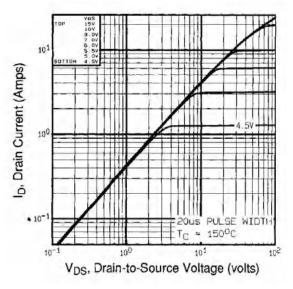
a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width \leq 300 µs; duty cycle \leq 2 %.





TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)







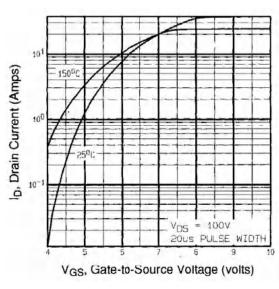
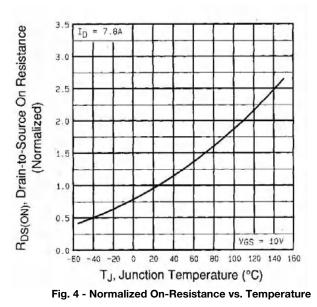


Fig. 3 - Typical Transfer Characteristics





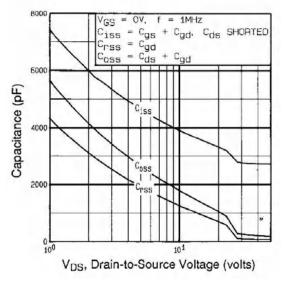


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

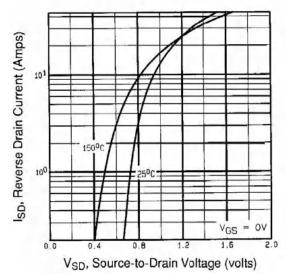


Fig. 7 - Typical Source-Drain Diode Forward Voltage

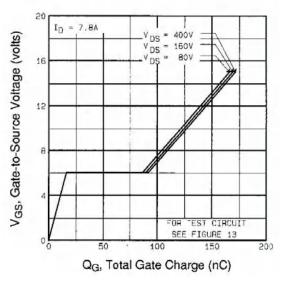
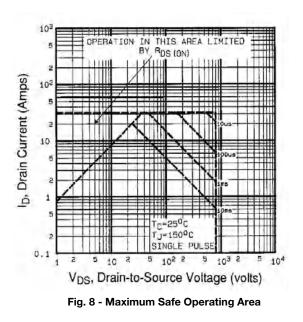


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage





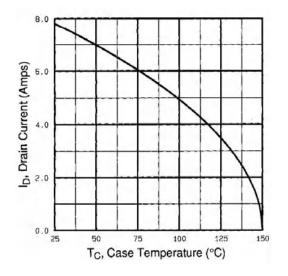


Fig. 9 - Maximum Drain Current vs. Case Temperature

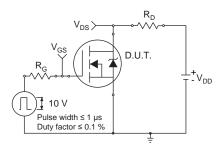


Fig. 10a - Switching Time Test Circuit

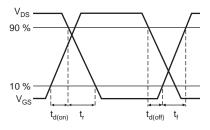


Fig. 10b - Switching Time Waveforms

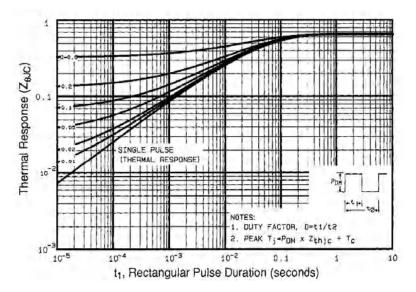


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



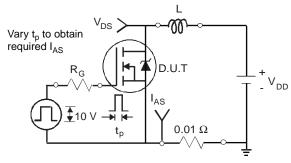


Fig. 12a - Unclamped Inductive Test Circuit

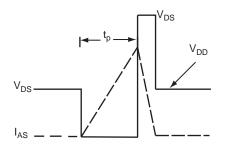


Fig. 12b - Unclamped Inductive Waveforms

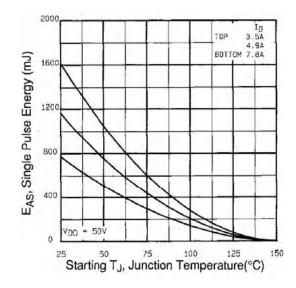


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

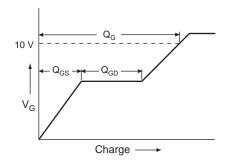
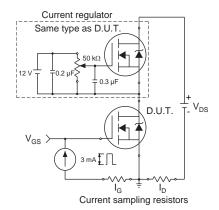


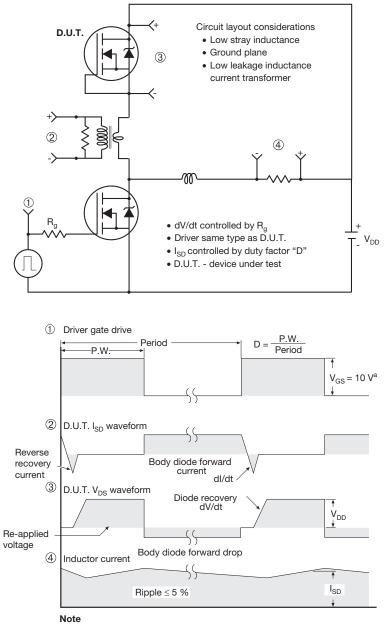
Fig. 13a - Basic Gate Charge Waveform







Peak Diode Recovery dV/dt Test Circuit

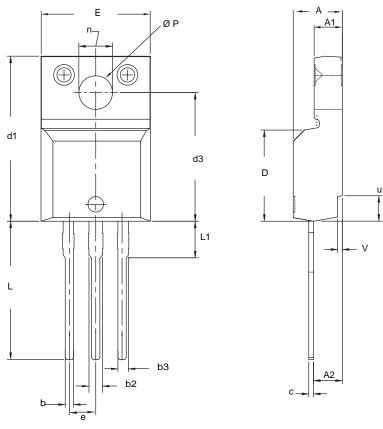


a. $V_{GS} = 5$ V for logic level devices

Fig. 14 - For N-Channel



TO-220 FULLPAK (HIGH VOLTAGE)



DIM.	MILLI	METERS	INC	CHES
	MIN.	MAX.	MIN.	MAX.
А	4.570	4.830	0.180	0.190
A1	2.570	2.830	0.101	0.111
A2	2.510	2.850	0.099	0.112
b	0.622	0.890	0.024	0.035
b2	1.229	1.400	0.048	0.055
b3	1.229	1.400	0.048	0.055
С	0.440	0.629	0.017	0.025
D	8.650	9.800	0.341	0.386
d1	15.88	16.120	0.622	0.635
d3	12.300	12.920	0.484	0.509
E	10.360	10.630	0.408	0.419
е	2.54	BSC	0.100 BSC	
L	13.200	13.730	0.520	0.541
L1	3.100	3.500	0.122	0.138
n	6.050	6.150	0.238	0.242
ØP	3.050	3.450	3.450 0.120	
u	2.400	2.500	0.094	0.098
V	0.400	0.500	0.016	0.020

Notes

1. To be used only for process drawing. 2. These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads. 3. All critical dimensions should C meet $C_{pk} > 1.33$. 4. All dimensions include burrs and plating thickness. 5. No chipping or package damage.



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